



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: **IECQ-L DQS 16.0003-14**

Issue No.: **12**

Status:

Current

Additional site to certification: **IECQ-L DQS 16.0003**

Initial Date: **2016-07-28**

Supersedes: **IECQ-L DQS 16.0003-14 Issue 11**

Issue date: **2026-09-15** Site Added: **2024-08-07**

CB Reference No.: **50600326 ITL**

Expiration: **2028-07-27**

Applicant: **Materials Analysis Technology (Shanghai) Ltd.**

Building 3 & 15 & 16, No. 1500, Zuchongzhi Rd., Zhangjiang Hi-tech Park, Shanghai, P.R.C., 201203, China

The organization, facilities and procedures have been assessed by the IECQ Conformity Assessment Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of the listed standard(s) or specification(s) for the testing of component product under the IECQ:

- **ISO/IEC 17025:2017** - General requirements for the competence of testing and calibration laboratories

Scope:

The materials analysis and failure analysis of semiconductors. The reliability testing of semiconductors in component level, board level, system level.
See attached Schedule.

-- Attached schedule(s): **IECQ-L_DQS_50600326 ITL., 08-10-26.pdf**

Issued by:

DQS Taiwan Inc.

8F, No. 23, Yuan Huan West Rd.
Taichung City, Feng Yuan Dist., Taiwan

<https://www.dqsglobal.com/zh-tw/>



Authorised person: **Bob CHEN**



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
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Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

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Appendix-1 (50600326 ITL)

Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
X-Ray imaging	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
IC Layout Imaging	T-OMI-3
Circuitry analysis	T-OMI-3
3D X-Ray microscope	T-EFA-3
Nano Probe	T-EFA-3
Secondary Ion Mass Spectrometry (SIMS)	T-SIM-3
Atomic Force Microscope (AFM)	T-SIM-3
Conductive atomic force microscopy (C-AFM)	T-SIM-3
Alpha-step stylus profiler	T-SIM-3

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X-Ray Photoelectron Spectroscopy (XPS)	T-SIM-3
Scanning Capacitance Microscopy (SCM)	T-SIM-3
High Temperature Operation Life test (HTOL)	IEC 60068-2-1, JESD22-A108
Low Temperature Operation Life test (LTOL)	IEC 60068-2-1, JESD22-A108
Bias Life test (BLT)	JESD22-A108
Highly Accelerated Stress test (HAST)	JESD22-A110
Temperature and Humidity with Bias test (THB)	JESD22-A101
Transmission Electron Microscope (TEM)	T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
Early Life Failure Rate (ELFR)	JESD22-A-108, AEC-Q100-008
Electrically Erasable Programmable ROM (EEPROM) Program / Erase Endurance and Data Retention Stress Test (NVCE / UCHTDR / PCHTDR / LTDR)	JESD22-A117
NVM Endurance, Data Retention, and Operational Life (NVCE)	AEC Q100-005

Technical Reviewer of DQS:

Paul Yang

Date: 08/10/2026

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